

Remote: SiPM radiation damage

Tuesday 19 November 2024 09:47 (27 minutes)

The current understanding of radiation tolerance of Silicon Photomultipliers (SiPMs) is reviewed. Methods to characterize irradiated SiPMs after their single photo-electron resolution is lost are discussed and ideas are presented on how to approach the development of radiation hard SiPMs.

Do you need a VISA letter for traveling to Canada ?

Yes

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Session Classification: Colliders (1) (Chair: Paolo Agnes, Feng Shi)

Track Classification: Invited Talk